



Frontiers in X-ray Materials Analysis
Thursday, October 9, 2014

FXMA Agenda 10/9/14

8:30AM - 9:00AM 9:00AM	Registration Welcome by Yale staff person
9:00AM - 9:30AM	Brian Jones, Bruker AXS Inc, Product Manager-XRD Recent advances in XRD instrumentation for Materials Analysis
9:30AM - 10:00AM	Michael Beauchaine Bruker XRFi, Business Development Manager Materials on a microscopic scale
10:00AM - 10:30AM	Morning Break
10:30AM - 11:00AM	Mark Rodriguez, Principle Member of Technical Staff Sandia National Labs, Albuquerque, NM Employing micro-XRF for detection of trace phases
11:00AM - 11:30AM	Jim Britten, Manager and Scientific Director, MAX Diffraction Facility, McMaster University, Hamilton, ON, Canada Texture Analyses of ZnTe and CdTe Thin Films Using XRD ³ , Jim Britten, Victoria Jarvis, Carley Miki and John Preston
11:30AM - 12:00PM	Jon Giencke, University of Wisconsin, Madison and Bruker AXS Inc, Application Scientist Structural Characterization of Ultra Thin Multiferroic Thin Films with Lab Based X-ray Diffraction
12:00PM - 1:30PM	Lunch and Tour
1:30PM - 2:00PM	Daniel Roberts, Research Scientist, Bristol-Myers Squibb, New Brunswick, NJ High Throughput Screening (HTS) applications using XRD
2:00PM - 2:30PM	Dmytro Nykypanchuk, Research Scientist, Brookhaven National Lab, Upton, NY Small Angle X-ray Diffraction Studies of Nanoparticle Self-assembly
2:30PM - 3:00PM	Afternoon Break
3:00PM - 3:30PM	Chunhua Tony Hu, X-ray Crystallographer, New York University, New York, NY Anti-counterfeit Protection of Pharmaceutical Products Using a Micro-X-ray Diffraction Protocol
3:30PM - 4:00PM	Shawn Gibb, VP of Engineering Crystal IS, Inc., Green Island, NY Characterization of Aluminum Nitride Materials via X-ray Diffraction